March 1996



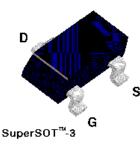
NDS351N N-Channel Logic Level Enhancement Mode Field Effect Transistor

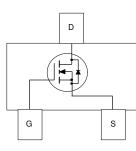
General Description

These N-Channel logic level enhancement mode power field effect transistors are produced using Fairchild's proprietary, high cell density, DMOS technology. This very high density process is especially tailored to minimize on-state resistance. These devices are particularly suited for low voltage applications in notebook computers, portable phones, PCMCIA cards, and other battery powered circuits where fast switching, and low in-line power loss are needed in a very small outline surface mount package.

Features

- 1.1A, 30V. $R_{DS(ON)} = 0.25\Omega$ @ $V_{GS} = 4.5V$.
- Proprietary package design using copper lead frame for superior thermal and electrical capabilities.
- High density cell design for extremely low R_{DS(ON)}.
- Exceptional on-resistance and maximum DC current capability.
- Compact industry standard SOT-23 surface mount package.





Absolute Maximum Ratings $T_A = 25^{\circ}C$ unless otherwise noted

Symbol	Parameter		NDS351N	Units
V _{DSS}	Drain-Source Voltage		30	V
V _{GSS}	Gate-Source Voltage - Continuous		20	V
I _D	Maximum Drain Current - Continuous	(Note 1a)	± 1.1	А
	- Pulsed		± 10	
P _D	Maximum Power Dissipation	(Note 1a)	0.5	W
		(Note 1b)	0.46	
T _J ,T _{STG}	Operating and Storage Temperature Range		-55 to 150	°C
THERMA	L CHARACTERISTICS	<u>.</u>		
R _{θJA}	Thermal Resistance, Junction-to-Ambient		250	°C/W
R _{θJC}	Thermal Resistance, Junction-to-Case	(Note 1)	75	°C/W

Symbol	Parameter	Conditions		Min	Тур	Max	Units
OFF CHA	RACTERISTICS						
BV _{DSS}	Drain-Source Breakdown Voltage	$V_{GS} = 0 V, I_{D} = 250 \mu A$		30			V
I _{DSS}	Zero Gate Voltage Drain Current	$V_{\rm DS} = 24 \text{ V}, \text{ V}_{\rm GS} = 0 \text{ V}$				1	μA
			T _J =125°C			10	μA
GSSF	Gate - Body Leakage, Forward	$V_{GS} = 12 \text{ V}, \text{ V}_{DS} = 0 \text{ V}$				100	nA
GSSR	Gate - Body Leakage, Reverse	$V_{GS} = -12 \text{ V}, \text{ V}_{DS} = 0 \text{ V}$				-100	nA
ON CHAF	ACTERISTICS (Note 2)	·					
$V_{\text{GS(th)}}$	Gate Threshold Voltage	$V_{DS} = V_{GS}, I_{D} = 250 \ \mu A$ $T_{J} = 125^{\circ} \mu$		0.8	1.6	2	V
			T _J =125°C	0.5	1.3	1.5	
R _{DS(ON)}	Static Drain-Source On-Resistance	V _{GS} = 4.5 V, I _D = 1.1 A			0.185	0.25	Ω
			T _J =125°C		0.26	0.37	
		$V_{GS} = 10 \text{ V}, \text{ I}_{D} = 1.4 \text{ A}$			0.135	0.16	
D(ON)	On-State Drain Current	$V_{GS} = 4.5 \text{ V}, V_{DS} = 5 \text{ V}$		5			Α
9 _{FS}	Forward Transconductance	$V_{DS} = 5 V, I_{D} = 1.1 A$			2.5		S
DYNAMIC	CHARACTERISTICS						
C _{iss}	Input Capacitance	$V_{DS} = 10 \text{ V}, \text{ V}_{GS} = 0 \text{ V},$ f = 1.0 MHz			140		pF
C _{oss}	Output Capacitance				80		pF
C _{rss}	Reverse Transfer Capacitance				18		pF
SWITCHI	NG CHARACTERISTICS (Note 2)						
d(on)	Turn - On Delay Time	$V_{DD} = 10 \text{ V}, \text{ I}_{D} = 1 \text{ A},$ $V_{GS} = 10 \text{ V}, \text{ R}_{GEN} = 50 \Omega$			9	15	ns
Tr	Turn - On Rise Time				16	30	ns
d(off)	Turn - Off Delay Time				26	50	ns
f	Turn - Off Fall Time				19	40	ns
ک ^و	Total Gate Charge	$V_{\rm DS} = 10 \text{ V}, \text{ I}_{\rm D} = 1.1 \text{ A},$			2	3.5	nC
Q _{gs}	Gate-Source Charge	$V_{gs} = 5 V$				1	nC
Q _{gd}	Gate-Drain Charge					2	nC

Electrical Characteristics (T _A = 25°C unless otherwise noted)							
Symbol	Parameter	Conditions	Min	Тур	Max	Units	
DRAIN-SOURCE DIODE CHARACTERISTICS AND MAXIMUM RATINGS							
l _s	Maximum Continuous Drain-Source Diode Forward Current				0.6	А	
I _{SM}	Maximum Pulsed Drain-Source Diode Forward Current				5	Α	
V _{SD}	Drain-Source Diode Forward Voltage	$V_{GS} = 0 V, I_{S} = 1.1 A$ (Note 2)		0.8	1.2	V	
Notes:		·	÷	•			

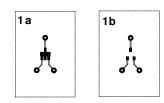
1. R_{g,M} is the sum of the junction-to-case and case-to-ambient thermal resistance where the case thermal reference is defined as the solder mounting surface of the drain pins. R_{g,M} is guaranteed by design while R_{g,A} is determined by the user's board design.

 $P_D(t) = \frac{T_J - T_A}{R_{\Theta J} \, \text{\AA}} = \frac{T_J - T_A}{R_{\Theta J} \, \text{\AA}^R_{\Theta C} \, \text{\AA}} = I_D^2(t) \times R_{DS \, (ON)} \mathfrak{g}_{T_J}$

Typical $\rm R_{_{H^{JA}}}$ using the board layouts shown below on 4.5"x5" FR-4 PCB in a still air environment:

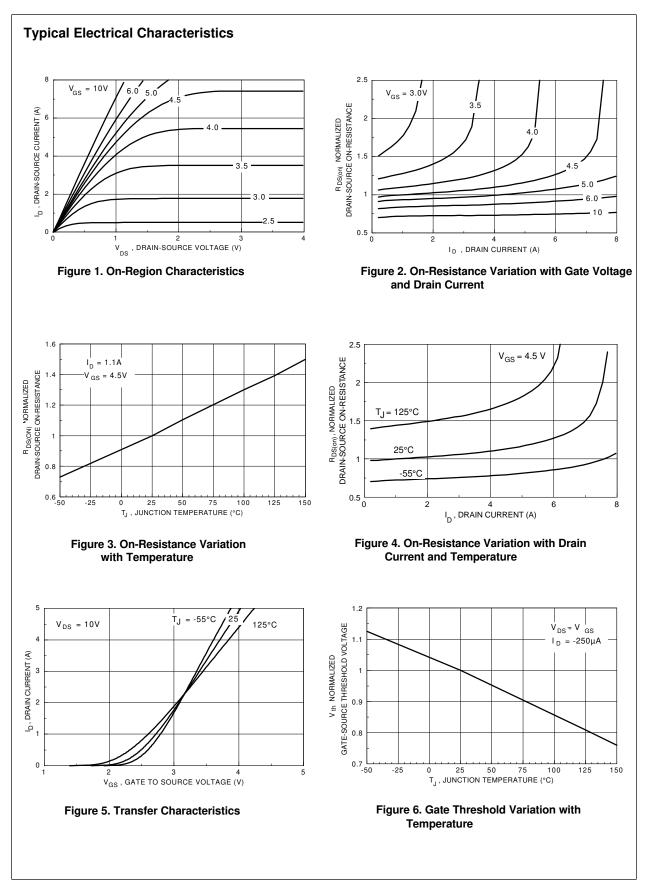
a. 250°C/W when mounted on a 0.02 in² pad of 2oz cpper.

b. 270°C/W when mounted on a 0.001 \mbox{in}^2 pad of 2oz cpper.

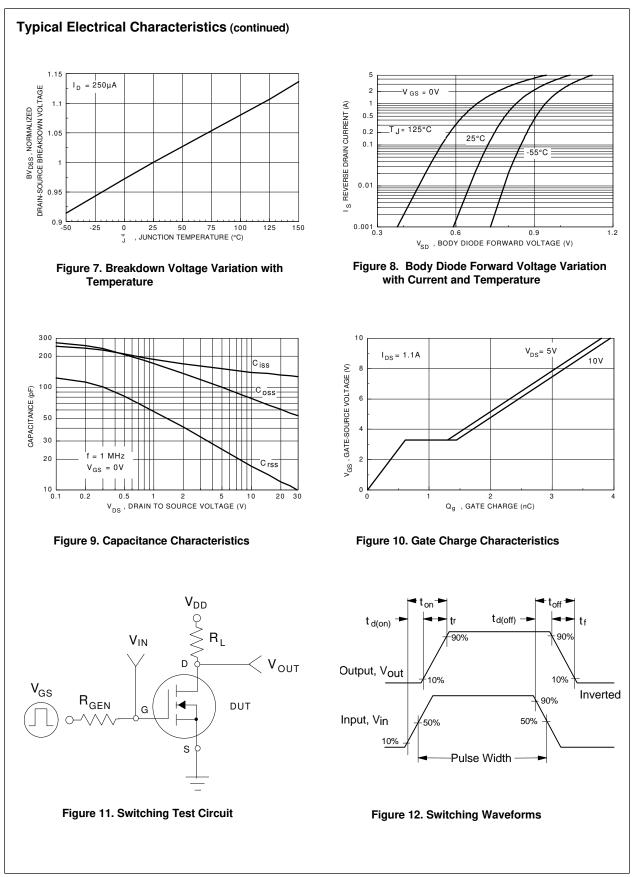


Scale 1 : 1 on letter size paper

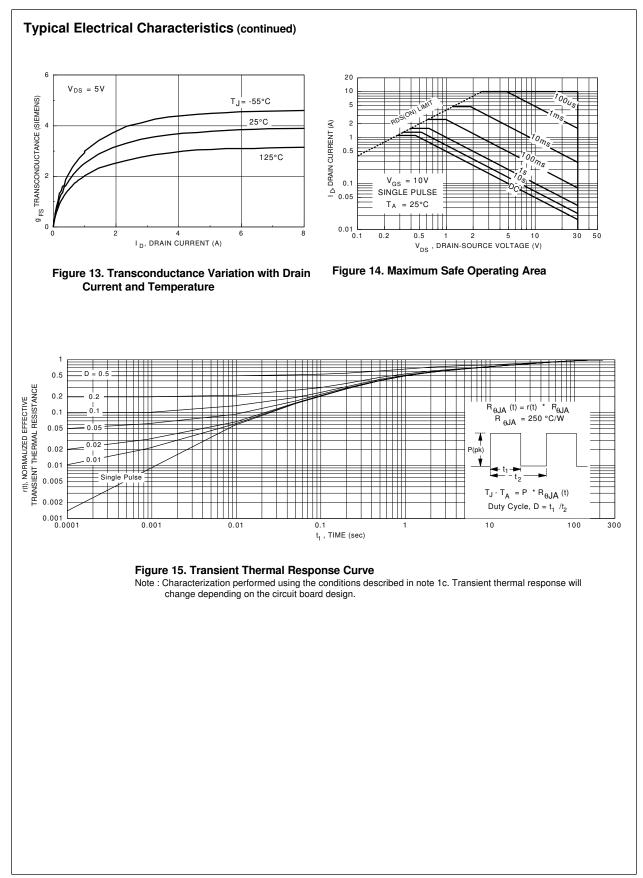
2. Pulse Test: Pulse Width \leq 300µs, Duty Cycle \leq 2.0%.



NDS351N Rev. E2



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